Application/Control No. Applicant(s)/Patent Under Reexamination 10/749,665 LI ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Thuy V. Tran 2821 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 04-2004 Ishidoshiro, Takashi 455/456.3 US-2004/0077361 A1 Α В US-2004/0038713 A1 02-2004 Okawa et al. 455/561 02-2004 Simmonds et al. 455/456.1 C US-2004/0023665 A1 US-2002/0164963 A1 11-2002 Tehrani et al. 455/101 D 03-2004 Ε US-6,707,425 B2 Louhi, Jyrki Tapio 342/359 F US-5,548,807 08-1996 Ueda, Tetsuro 370/334 G US-US-Н

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